

CALL FOR PAPERSIEEE Transactions on Nanotechnology
Special Section***Nanotechnology for Instrumentation and Measurement***

Instrumentation and measurement are of importance when charactering, testing and employing novel devices and materials. These areas assume a particular importance at the “nano” scales in which electrical and physical quantities encounter new challenges. The proposed special section will be comprised of high impact papers with particular emphasis on the application area of instrumentation and measurement and its relation to nanotechnology. Original research contributions and review papers, not limited to the ones presented at nanofim2015, are sought including (but not limited to) the following topics:

General and dedicated devices	Fabrication and characterization of sensors and transducers
Nanoimaging	Signal and image processing
Metrology, reliability and testing	General and <i>ad hoc</i> instrumentation
Nanotechnology and plasma	Biomedical applications
Environmental applications	Industrial applications
Automotive	Mechatronics
Nanomedicine	Light and lightning
Nanoptics and Nanophotonics	Packaging and Nanomaterials
Networking	Modeling
Bio-molecular and Biotechnology	Energy
Aeronautics and aerospace	

Extended versions of accepted and presented papers at Nanofim2015 (<http://nanofim2015.unisalento.it>) are encouraged but they will still undergo the peer review process; authors for this Special Section are requested to expand the workshop version to contain at least 40% new material. All manuscripts must be submitted on-line using the IEEE TNANO manuscript template and *Information for Authors*, via the *IEEE Manuscript Central™* found at <https://mc.manuscriptcentral.com/tnano>. On submission, authors must select the “*Special Issue*” manuscript type instead of “Regular Paper.” Manuscripts must focus on nanotechnology for instrumentation and measurement as reflected by technical content and references.

<u>Deadlines:</u>	Manuscript Submission:	October 1, 2015
	First decision to authors:	December 15, 2015
	Revision due (if necessary):	February 1, 2016
	Final notification (acceptance/rejection):	March 1, 2016
	Final manuscripts due:	March 30, 2016
	Special section publication:	5 th issue of 2016

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